8.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

H. MIYAGAWA et al

Serial No. 10/086,718

Group Art Unit: 2858

Filed: March 4, 2002

Examiner: V. Nguyen

For: MODULATION SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE

AND TESTING METHOD FOR OSCILLATION CIRCUIT

REPLY

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

October 23, 2003

Sir:

In response to the Office Action mailed April 23, 2003, please amend the above-identified application as follows. A petition and fee for a Three-month Extension of Time accompany this Reply.